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## LIST OF DOCUMENTS CITED BY APPLICANT

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Kiyoshi NAKAI et al.

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## U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-class	Filing Date
TTN	AA	5,602,772	2/11/97	Nakano et al.	365	51	
TTN	AB	5,629,887	5/13/97	Nakano et al.	365	51	
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

## FOREIGN PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Country	Class	Sub-class	Translation
TTN	AJ	10-303387	11/13/98	JAPAN			abstract
TTN	AK	7-254650	10/3/95	JAPAN			
	AL						
	AM						
	AN						
	AO						

**OTHER** (including author, title, date, pertinent pages, etc.)

	AP	
	AQ	
	AR	

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